

# **VDIC NAND FLASH MEMORY**

## **VDNF64G08XS50XX4V25 USER MANUAL**

**Version : A0**

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# VDIC-NAND Flash Memory

## HIGH-SPEED 3.3V 8G × 8bit

### 1 Description

The VDNF64G08XS50XX4V25 is a 64G-bit NAND Flash Memory device and operates Voltage at 3.3V.

This device contains 4 chips and each chip is composed of two dies. Each chip is offered in 2Gx8bit format and can be operated independently and simultaneously by software. The I/O ports of the two dies in each chip are connected together. The control pins (ALE,CLE,#WE,#RE) of all dies in the device are connected together.

This VDNF64G08XS50XX4V25 device include an asynchronous data interface for high-performance I/O operations .These devices use a highly multiplexed 8-bit bus (DQx) to transfer commands, address, and data. There are five control signals used to implement the asynchronous data interface: #CE, CLE, ALE, #WE, and #RE. Additional signals control hardware write protection (#WP) and monitor device status (#R/B).

This hardware interface creates a low pin-count device with a standard pin out that remains the same from one density to another, enabling future upgrades to higher densities with no board redesign

The VDNF64G08XS50XX4V25 provides the most cost-effective solution for the solid state application market and is an optimum solution for large nonvolatile storage applications such as solid state data storage and advanced embedded control applications.

### 2 Features

- Voltage Supply
  - 3.3V device: 2.7 ~ 3.6 V
- Organization
  - page size x8:4320 bytes(4096+224 bytes)
  - Block size:128 pages(512K+28K bytes)
  - Plane size: 2 Planesx2048 blocks per Plane
  - Device size:64G:16384block
- Asynchronous I/O performance
  - UP to asynchronous timing mode 4
  - 'RC/^WC:25ns ( MIN )
- Array performance
  - Read page : 25μs(Max.)
  - Program time : 230μs(Typ.)
  - Block Erase Time : 700μs (Typ.)
- First block (block address 00h) is valid when shipped from Factory. for minimum required ECC, see Error

## Management

- RESET(FFh) required as first command after power on
- Operation status byte provides software method for detecting
  - Operation completion
  - Pass/fail condition
  - Write-protect status
- Copyback operations supported within the plane from which data is read
- Package

SOP-50

### 3 Block Diagram

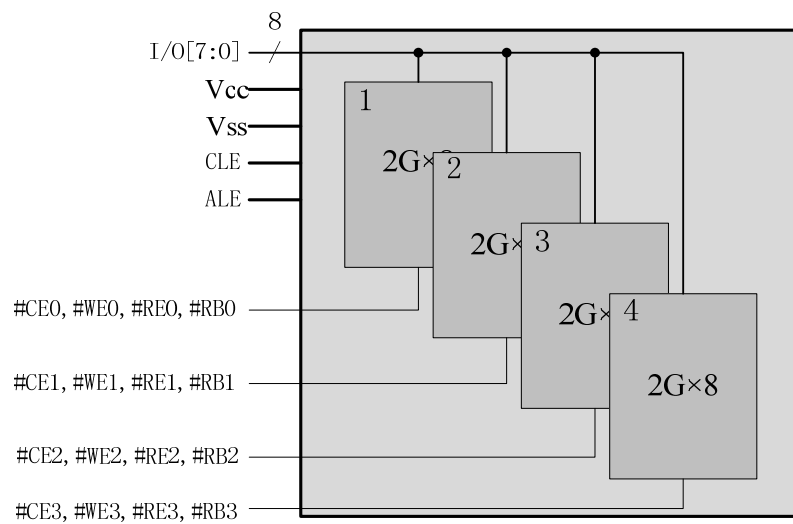


Figure 1 Block diagram

## 4 Pin Descriptions-sop-50

Pin Id	Pin #		Pin Id
NC	1	50	NC
NC	2	49	NC
NC	3	48	NC
NC	4	47	NC
#R/B3	5	46	#RE3
#R/B2	6	45	I/O7
#R/B1	7	44	I/O6
#R/B0	8	43	I/O5
#RE0	9	42	I/O4
#CE0	10	41	#RE2
#CE1	11	40	#RE1
#CE2	12	39	VCC
VCC	13	38	VCC
VSS	14	37	VSS
#CE3	15	36	VSS
NC	16	35	VSS
CLE	17	34	NC
ALE	18	33	I/O3
#WE0	19	32	I/O2
#WP	20	31	I/O1
#WE1	21	30	I/O0
#WE2	22	29	NC
#WE3	23	28	NC
NC	24	27	NC
NC	25	26	NC

Figure 2 Pin configuration

Table 1 Pin description

Name	Function
I/O0~I/O7	<b>DATA INPUTS/OUTPUTS</b> The DQ pins are used to input command, address and data, and to output data during read operations. The DQ pins float to high-z when the chip is deselected or when the outputs are disabled.
CLE	<b>COMMAND LATCH ENABLE</b> The CLE input controls the activating path for commands sent to the command register. When active high, commands are latched into the command register through the DQ ports on the rising edge of the #WEn signal.
#CEn	<b>CHIP ENABLE.</b> When #CEn is Low, the command input cycle becomes valid. When #CEn is High, all inputs are ignored.
ALE	<b>ADDRESS LATCH ENABLE</b> The ALE input controls the activating path for address to the internal address registers. Addresses are latched on the rising edge of #WEn with ALE high.
#REn	<b>READ ENABLE</b> The #REn input is the serial data-out control, and when active drives the data onto the DQ bus. Data is valid $t_{REA}$ after the falling edge of #REn which also increments the internal column address counter by one.
#WEn	<b>WRITE ENABLE</b> The #WEn input controls writes to the DQ port. Commands, address and data are latched on the rising edge of the #WEn pulse.
#WP	<b>WRITE PROTECT</b> The #WP pin provides inadvertent write/erase protection during power transitions. The internal high voltage generator is reset when the #WP pin is active low.

Name	Function
#R/Bn	<b>READY/BUSY OUTPUT</b> The #R/Bn output indicates the status of the device operation. When low, it indicates that a program, erase or random read operation is in progress and returns to high state upon completion. It is an open drain output and does not float to high-z condition when the chip is deselected or when outputs are disabled.
VCC	<b>POWER.</b>
VSS	<b>GROUND</b>

## 5 Electrical Specifications

### 5.1 Absolute Maximum Ratings

Table 2 Absolute maximum ratings

Characteristics	Symbol	Maximum ratings	Unit
Supply Voltage relative to V <sub>SS</sub>	V <sub>CC</sub>	-0.6 ~ +4.6	V
Voltage on any Pin relative to V <sub>SS</sub>	V <sub>IN</sub>	-0.6 ~ +4.6	V
Power Dissipation	P <sub>D</sub>	2.0	W
Operating Temperature Range	T <sub>OPR</sub>	-55 ~ +125	°C
Storage Temperature Range	T <sub>STG</sub>	-65 ~ +150	°C

### 5.2 Recommended DC Operating Conditions

Table 3 Recommended DC operating condition

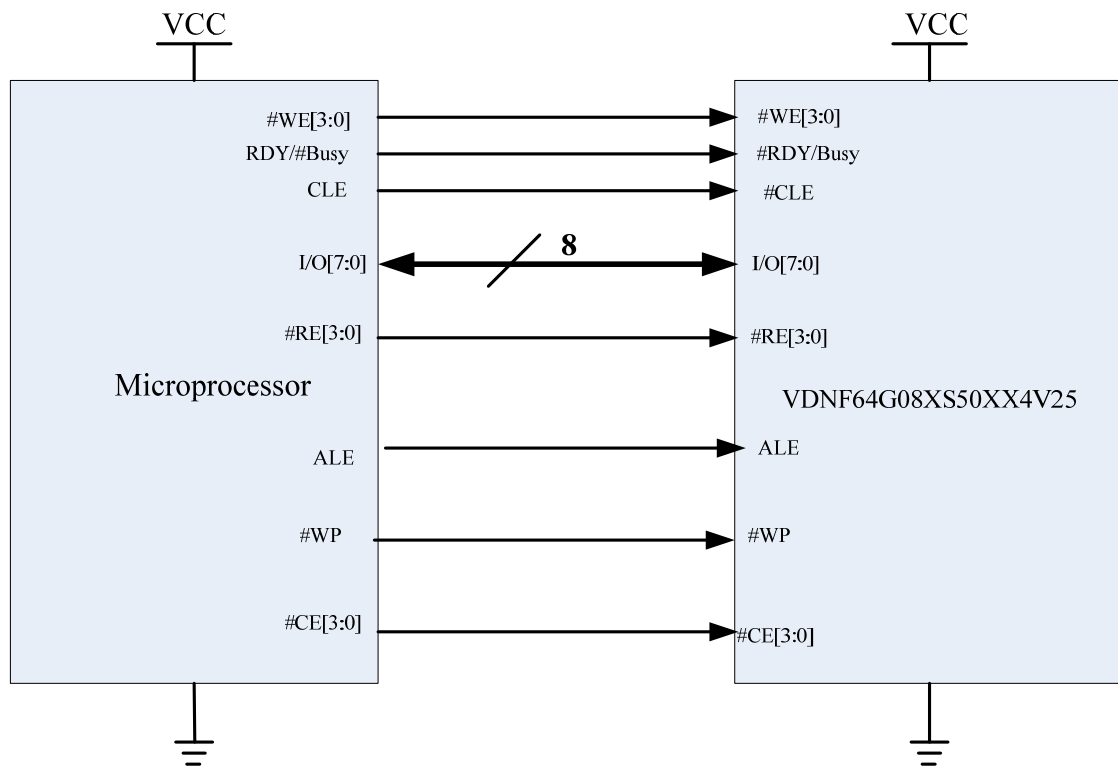
Parameter	Symbol	Min	Typ	Max	Unit
V <sub>CC</sub> Supply voltage	V <sub>CC</sub>	2.7	3.3	3.6	V
Input high voltage	V <sub>IH</sub>	0.8×V <sub>CC</sub>	—	V <sub>CC</sub> +0.3	V
Input low voltage	V <sub>IL</sub>	-0.3	—	0.2×V <sub>CC</sub>	V

### 5.3 DC Characteristics and Operating Conditions

Table 4 DC characteristics

Parameter	Symbol	Test Conditions	Min	Max	Unit
Low Level Output Voltage	V <sub>OL</sub>	V <sub>CC</sub> =2.7V , I <sub>OL</sub> =2.1 mA	-	0.4	V
High Level Output Voltage	V <sub>OH</sub>	V <sub>CC</sub> =2.7V , I <sub>OH</sub> =-0.4mA	2.4	-	V

## 6 Typical Application



## 7 ORDERING INFORMATION

1	2	3	4	5	6	7	8	9	10	11	12	13
<u>VD</u>	<u>NF</u>	<u>64G</u>	<u>08</u>	<u>X</u>	<u>S</u>	<u>50</u>	<u>X</u>	<u>X</u>	<u>4</u>	<u>V</u>	<u>25</u>	-
VDIC												
NAND FLASH												
Capability: 64G bit												
Bus Width: 8 bit												
R= Radiation Data Tested; V= Generic Radiation Data Available												
Package: SOP												
Pin Quantity: 50 Pin												
Temperature: E=0~+70°C;I=-40~+85°C;M=-55~+125°C												
Quality: E= Sample; B= Industry; M=Military; S= Space												
Stacking Layer: 4layer												
Power Supply : 3.3V												
Speed: 25ns												
Version: First Version												

Table 5 Ordering information

Part Number	Capacity (bit)	Bus Width (bit)	Radiation			Packaging	Temperature ( °C )
			TID <sup>1</sup>	SEL <sup>2</sup>	SEU <sup>3</sup>		
VDNF64G08VS50EE4V25	64G	08	-	-	-	SOP50	0 ~ + 70
VDNF64G08VS50IB4V25	64G	08	-	-	-	SOP50	-40 ~ + 85
VDNF64G08VS50MM4V25	64G	08	-	-	-	SOP50	-55 ~ + 125
VDNF64G08RS50MS4V25	64G	08	>60	>60	1.3	SOP50	-55 ~ + 125

<sup>1</sup> TID: Total Dose (Krad(Si))

<sup>2</sup> SEL: LET Threshold (Mev.cm<sup>2</sup>/mg)

<sup>3</sup> SEU:SEU Threshold (Mev.cm<sup>2</sup>/mg)



### 8 PACKAGE DIMENSIONS

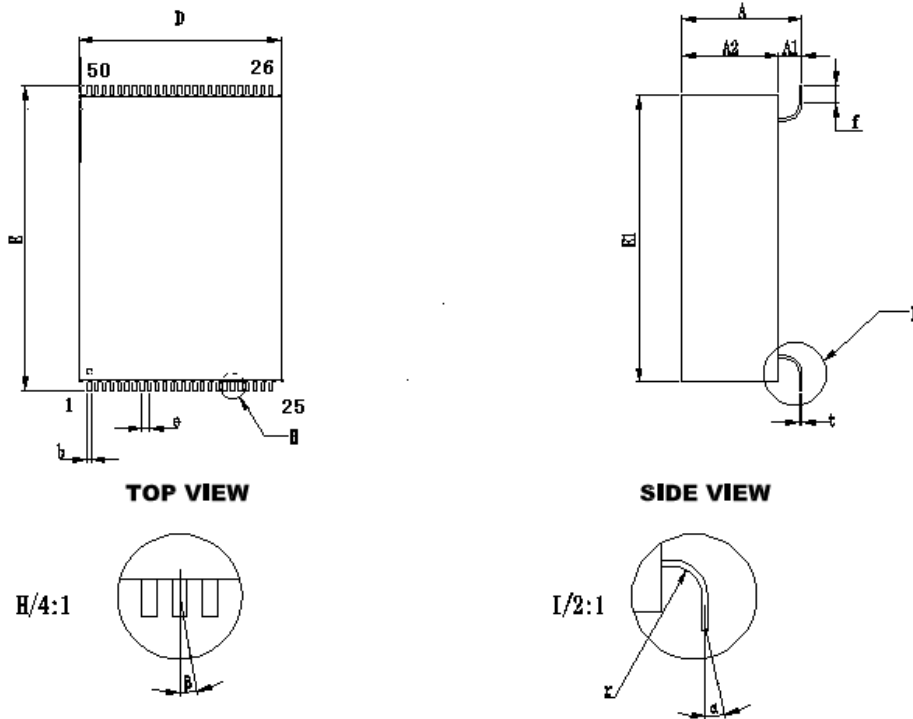


Figure 3 Package dimensions

Table 6 Dimensions information

	Min	Max
A	7.40	7.90
A2	6.20	6.60
D	13.30	13.70
E	19.80	20.20
E1	18.80	19.20
f	1.20	
b	0.25	
e	0.50	
r	1.00	
t	0.20	
$\alpha$	$\leq 3^\circ$	
$\beta$	$\leq 3^\circ$	
NOTE: 1. Unit: mm 2. $A1 = A - A2$		

## 9 REVISION HISTORY

**Table 7 Revision history**

Revision	Date	Description of Change
A0	Aug 16,2018	First Created